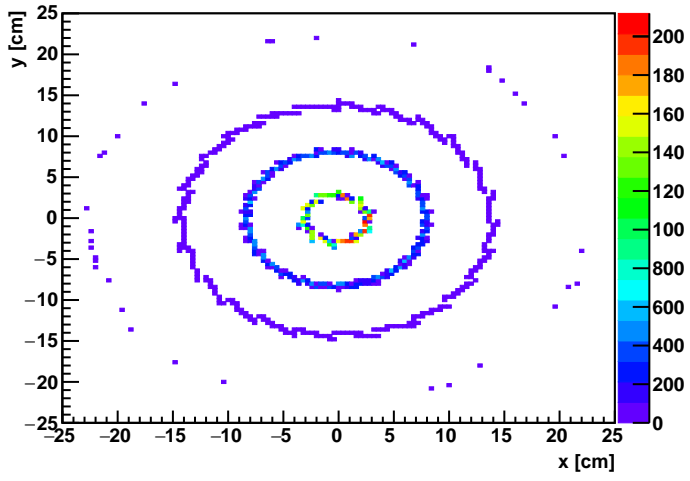
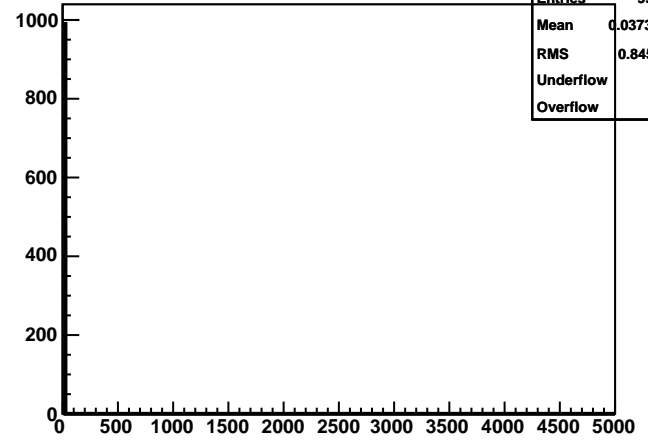


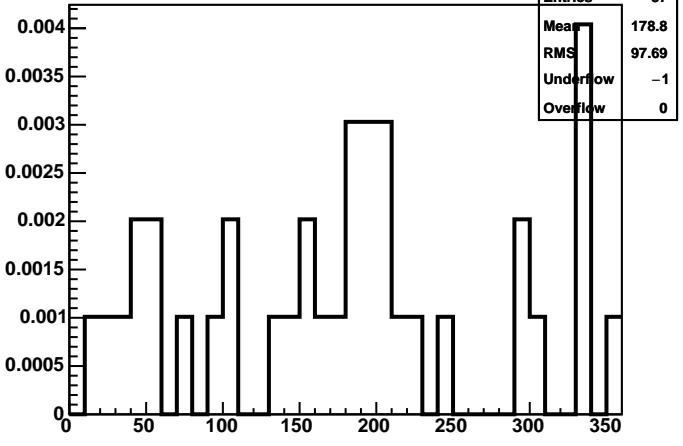
PIXEL, IST, SSD: Distribution of hits in XY



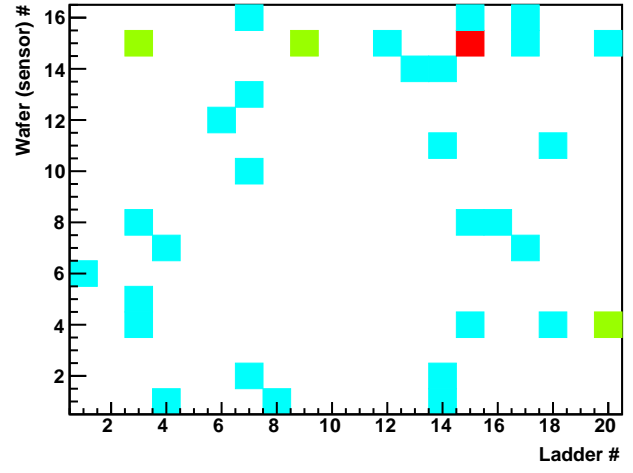
StE point: # hits sst



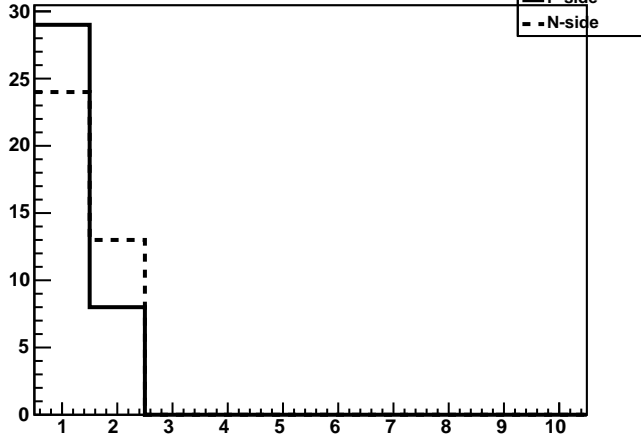
StE SST: ϕ of hits (per event)



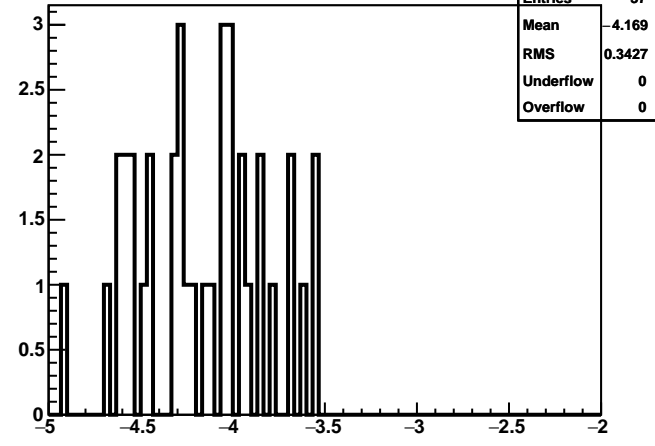
StE SST: wafer id vs ladder id (per event)

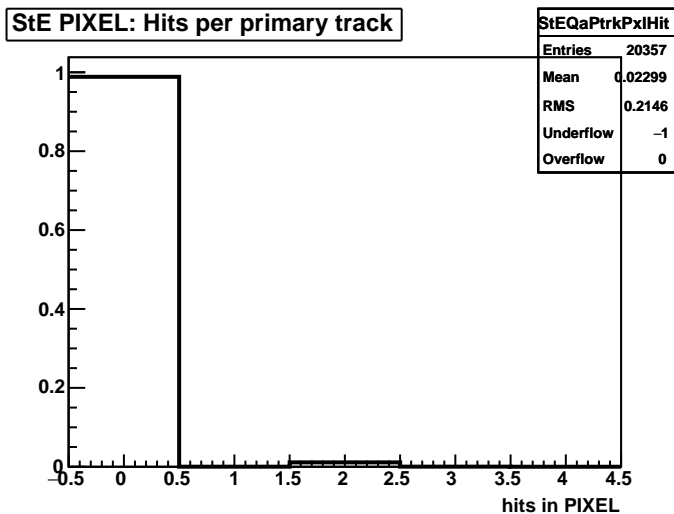
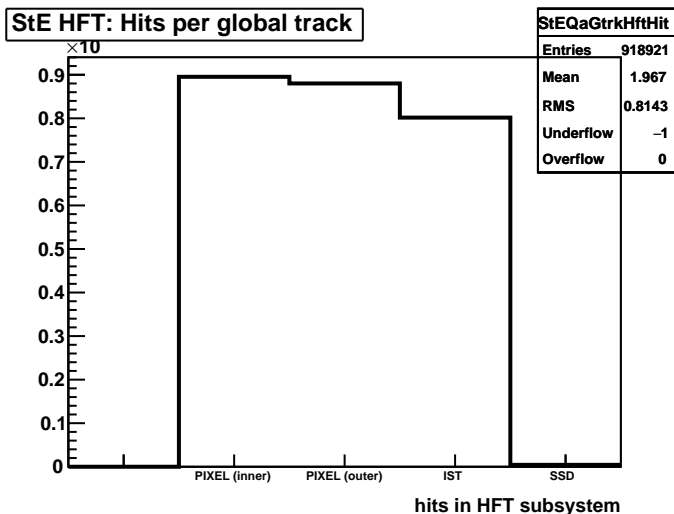
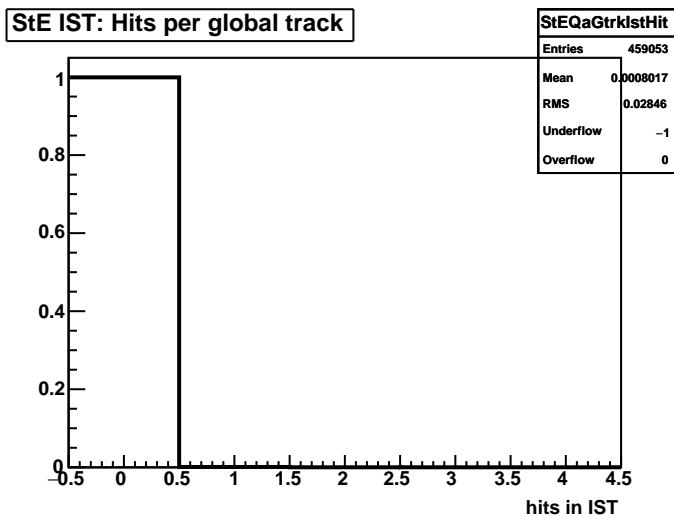
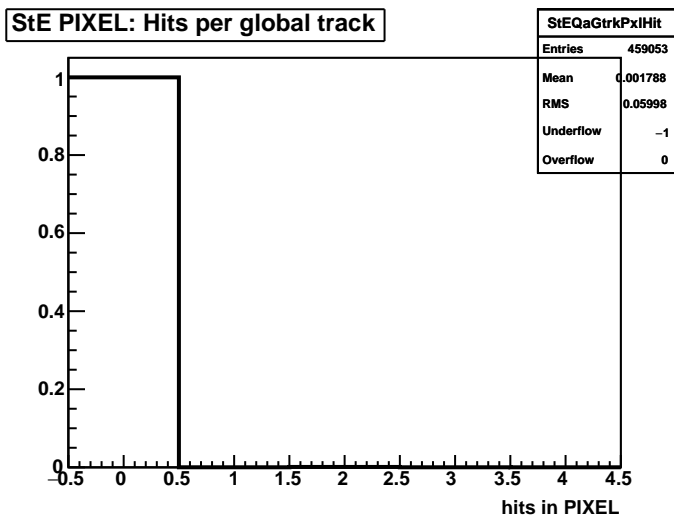
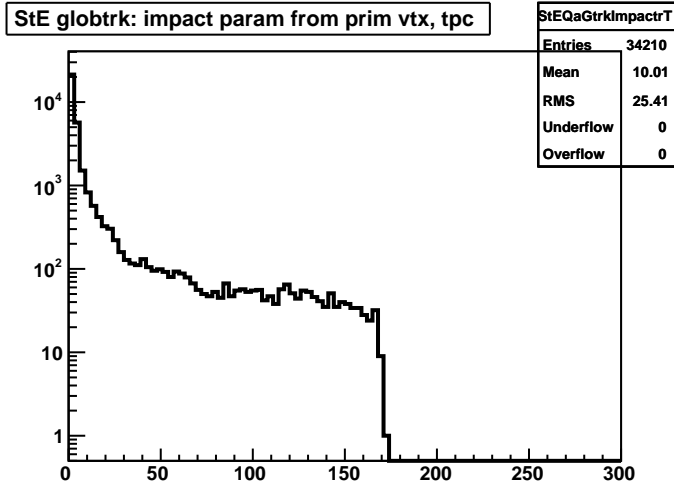
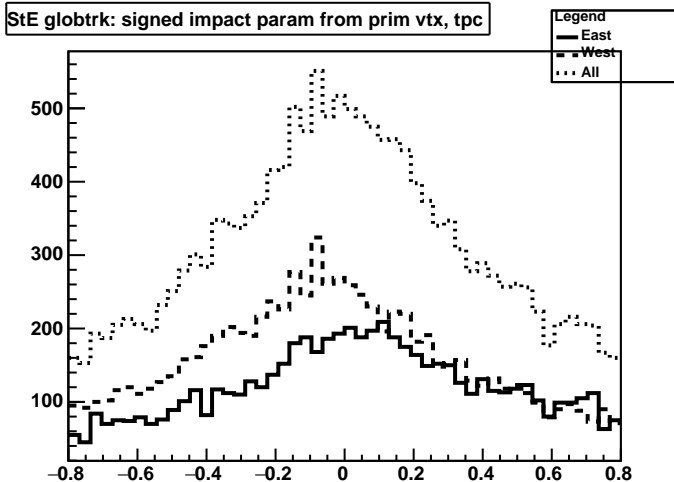


StE SST: size of clusters

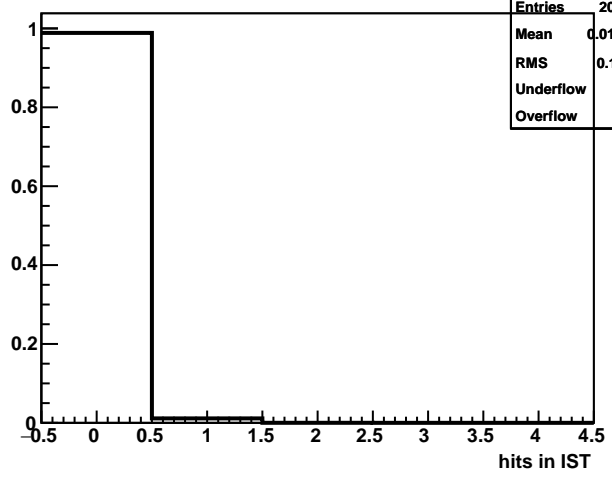


StE SST: log10(energy) of hits

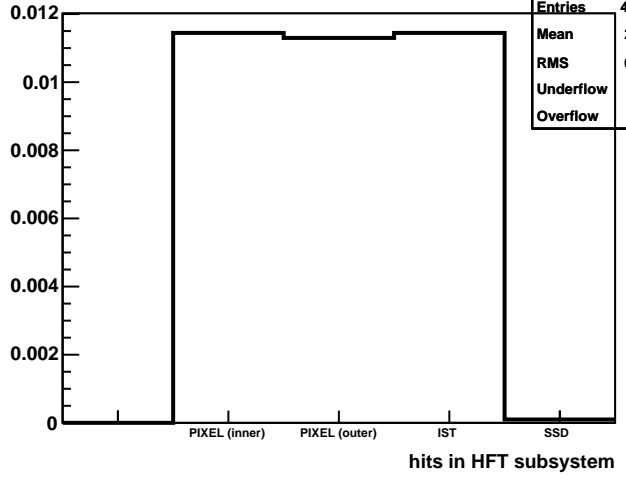




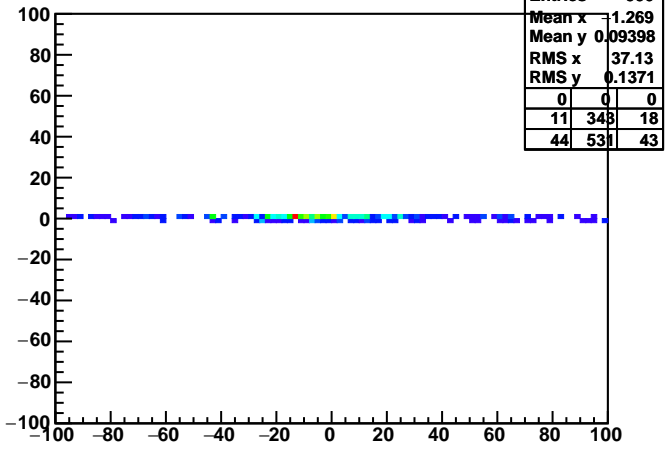
StE IST: Hits per primary track



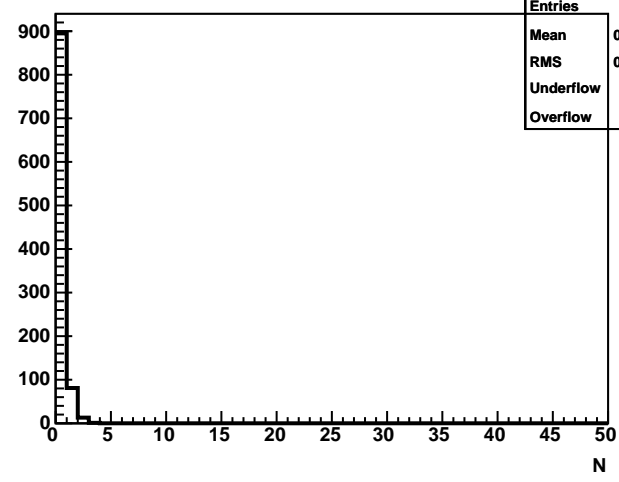
StE HFT: Hits per primary track



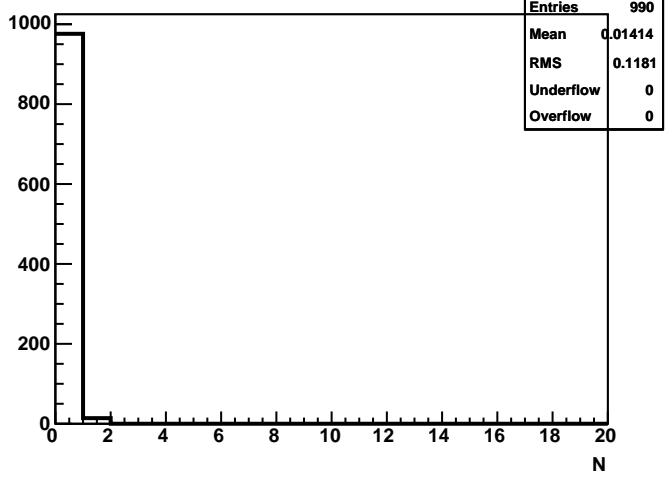
StE VPD vtxz vs TPC vtxz



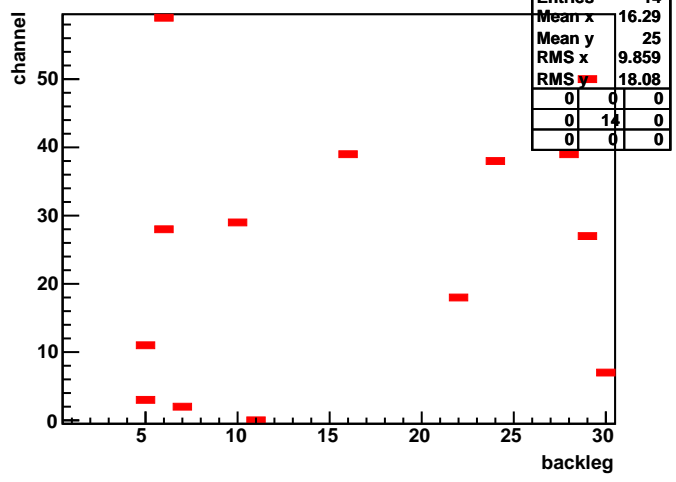
StE Number of MTD hits per event



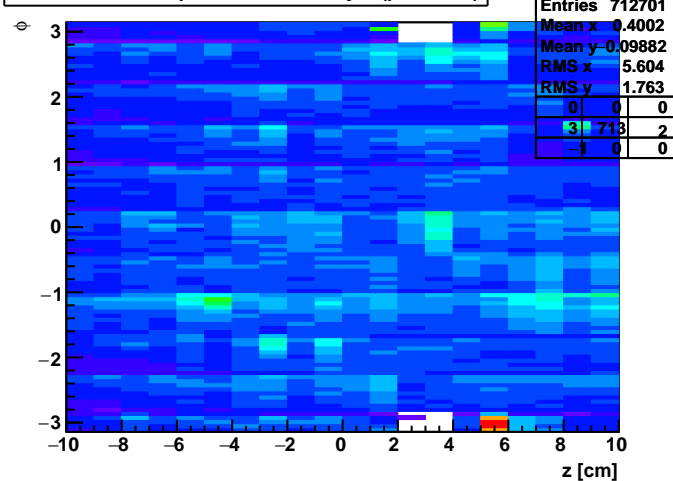
StE Number of matched MTD hits per event



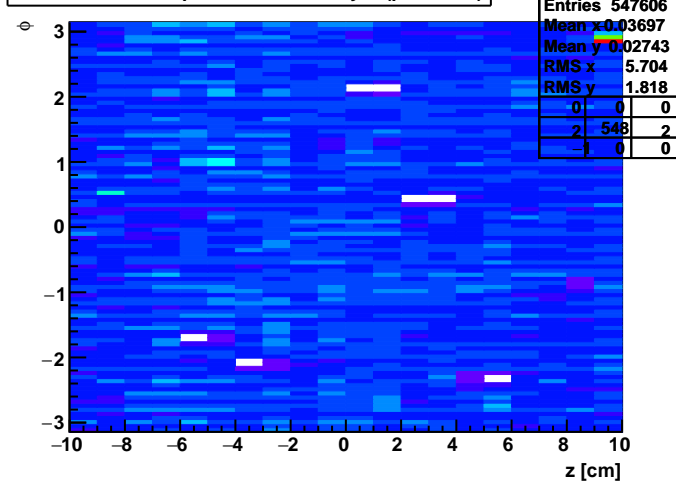
StE MTD: channel vs backlog of matched hits



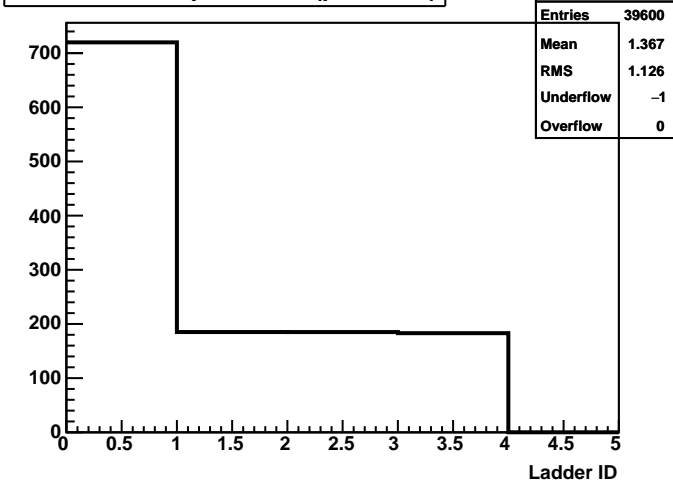
StE PIXEL: hits vs phi vs z in inner layer (per event)



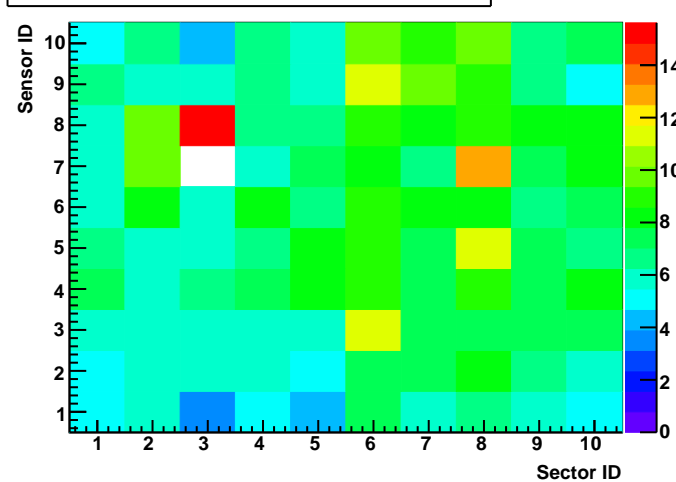
StE PIXEL: hits vs phi vs z in outer layer (per event)



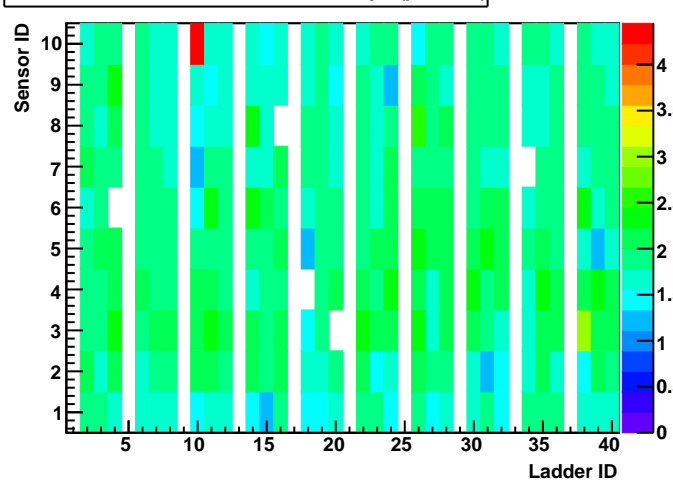
StE PIXEL: hits per ladder (per event)



StE PIXEL: hits vs sector vs sensor in inner layer (per event)



StE PIXEL: hits vs ladder vs sensor in outer layer (per event)



StE PIXEL: Hits in inner vs outer layer (per event)

